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AMENDMENTS TO THE SPECIFICATION

On page 6, amend the paragraph beginning at line 17 as follows:

Figure 3[[,]] shows the resulting electrical circuit for the relevant portion 300 of the memory array when row 280 is grounded. As shown, memory element 310 to be sensed is connected between a grounded row line 280 and a particular column line 320. Also connected to the column line 320 are is a plurality of other resistive memory elements (e.g., elements 330, 340, 350, 360, 370) each of which is connected at its opposite end to a pull-up voltage source Va 215 through a respective row line 210. In addition, a respective sensing circuit 400 is connected to the column line 320. The sensing circuit 400 includes a voltage supply that maintains the column line 320 at electrical potential Va.

On page 8 amend the paragraph beginning at line 12 as follows

The resistance measuring circuit 500 outputs a bit stream from an output 900 of a comparator 910. The ratio of logic one bits to a total number of bits (or, in and other another aspect of the invention, the ratio of logic one bits to logic zero bits) in the bit stream yields a numerical value. This numerical value corresponds to the current that flows through the resistance 520 in response to a known applied voltage. For example, assume that a current source can deliver current at two discrete current levels, corresponding to two different states of a logical input signal. When the signal is in logic one state, the source delivers, for example, 2 μ A. When the signal is in a logic zero state, the source delivers, for example, 0 μ A. The logical input signal is monitored over a finite time span corresponding to a number of bit-length time periods. Over that time span, the number numbers of logic one and logic zero bits are recorded. By

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straightforward algebra, the average current delivered by the current source over the corresponding time span may be calculated as follows:

IAVG =
$$(number of logic 1 bits)*2\mu A + (number of logic 0 bits)*0\mu A$$

total number of bits in the signal

As an example, if, over a time span corresponding to 4 cycles, there is one logic one bit and three logic zero bits then the average current over the four cycles is $0.5\mu A$.

IAVG=
$$\frac{1*2\mu A + 3*0\mu A}{4}$$
 = 0.5 μA

On page 14, amend the paragraph beginning at line 3 as follows:

Figure <u>7</u> 9 shows a computer system 1200 including a digital memory 1210 having a resistance measuring memory cell sensor according to the invention. The computer 1200, as shown includes a central processing unit (CPU) 1220, for example, a microprocessor, that communicates with one or more input/output (I/O) devices 1230 over a bus 1240. The computer system also includes peripheral devices such as disk storage 1250 and a user interface 1260. It may be desirable to integrate the processor and memory on a single IC chip.